

# Search Notes



Application/Control No.

10/808,515

Examiner

Sin J. Lee

Applicant(s)/Patent under  
Reexamination

HANAMOTO ET AL.

Art Unit

1752

## SEARCHED

Class	Subclass	Date	Examiner
430	270-1	5/30/05	SJL
↓	326	↓	↓
↓	905	↓	↓
↓	910	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR